

ENSC Batch No. _____ Wafers Started _____ Date _____

Material _____ Orientation _____ Size _____ Thickness _____

Resistivity _____ Type _____

Wafer Vendor _____ Vendor Batch # _____ SFU P.O. _____

| Process Step # | Process Conditions | Oper & Wafer # | Comments |
|----------------|---|----------------|----------|
| _____A | RCA clean and Oxidation | | |
| _____B | Photolithography 1: define and etch windows in oxide for boron diffusion | | |
| _____C | Mod RCA clean and Boron diffusion | | |
| _____D | Low Temperature Oxidation | | |
| _____E | Oxide strip | | |
| _____F | RCA clean, drive-in and oxidation | | |
| _____G | Photolithography 2: define and etch windows in oxide for phosphorus diffusion | | |
| _____H | RCA clean and Phosphorus diffusion | | |
| _____I | Drive-in and oxidation | | |
| _____J | Photolithography 3: define and etch contact cuts for Al | | |
| _____K | Sputter Al (will run only brief demo in class. Class wafers will be sputtered outside of class) | | |
| _____L | Photolithography 4: define and etch aluminum | | |
| _____M | Anneal aluminum | | |
| _____N | Probe test structures | | |
| _____O | Dice and bond | | |